Amendments to the Claims:

This listing of claims will replace all prior versions, and listings, of claims in the application:

Listing of Claims:

Claim 1 (currently amended): Beam current measuring apparatus comprising:

a magnetism shielding part for shielding an external magnetic field; and

a magnetic field sensor arranged in the shielding space generated by said magnetism

shielding part, said beam current measuring apparatus measuring, by using said magnetic

field sensor, a magnetic field where a beam current to be measured is generated,

wherein said magnetic field sensor has a magnetic flux/feedback current conversion coefficient of 8×10-15 Wb/A or above, the magnetic flux/feedback current conversion coefficient representing a ratio of a feedback current flowing to a feedback coil with respect to a change amount of magnetic flux passing through the magnetic field sensor.

Claim 2 (original): The beam current measuring apparatus according to claim 1, wherein said magnetic field sensor has a magnetic flux/feedback current conversion coefficient of 2×10-12 Wb/A or below.

Claim 3 (currently amended): The beam current measuring apparatus according to claim 1 or 2, wherein said magnetic field sensor has a magnetic flux/feedback current conversion coefficient of 1×10-12 Wb/A or below.

Claim 4 (original): Beam current measuring apparatus comprising:

a magnetism shielding part for shielding an external magnetic field; and

a magnetic field sensor arranged in the shielding space generated by said magnetism shielding part, said beam current measuring apparatus measuring, by using said magnetic field sensor, a magnetic field where a beam current to be measured is generated,

wherein said magnetic field sensor has a magnetic flux sensitivity of 2×10-18 Wb/V or above.

Claim 5 (currently amended): The beam current measuring apparatus according to claim 4, wherein said magnetic field sensor has a magnetism magnetic flux sensitivity of 5×10-15 Wb/V or below.

Claim 6 (currently amended): The beam current measuring apparatus according to claim 4-or-5, wherein said magnetic field sensor has a magnetic flux sensitivity of 2×10-15 Wb/V or below.

Claim 7 (currently amended): The beam current measuring apparatus according to any one of claims 1 through 6 claim 1, wherein said magnetic field sensor is a SQUID.

Claim 8 (currently amended): The beam current measuring apparatus according to any one of claims 1 through 6 claim 1, wherein said magnetic field sensor is a high-temperature superconducting SOUID.

Claim 9 (currently amended): The beam current measuring apparatus according to any one of claims 1 through 8 claim 1, wherein said magnetic field sensor comprises a magnetism shielding part for magnetically shielding from an external magnetic field a sensor part that senses magnetic flux to be measured.

Claim 10(original): The beam current measuring apparatus according to claim 9, wherein said magnetism shielding section comprises a superconductor.

Claim 11 (original): The beam current measuring apparatus according to claim 9, wherein said magnetism shielding section comprises a high-temperature superconductor.

Claim 12 (currently amended): The beam current measuring apparatus according to claim 10 or 11, wherein said magnetism shielding section comprises a gap.

Claim 13 (currently amended): The beam current measuring apparatus according to any one of claims 1 through 12 claim 1, wherein said magnetic field sensor comprises an electric field shielding part for shielding from an external electric field a sensor part that senses magnetic flux to be measured.

Claim 14 (currently amended): The beam current measuring apparatus according to any one of claims 1 through 13 claim 1, wherein said magnetism sensor comprises a mechanism for collecting a magnetic field generated by a beam current to be measured.

Claim 15 (original): The beam current measuring apparatus according to claim 14, wherein said mechanism for collecting a magnetic field is a coil including a superconducting wire wound around a core of a soft magnetic material or a cylinder whose surface is coated with a high-temperature superconductor and whose outer periphery has a bridge part partially including a high-temperature superconductor.

Claim 16 (currently amended): A beam current measuring method using the beam current measuring apparatus according to any one of claims 1 through 15 claim 1, comprising the step of:

arranging a magnetic field sensor of said beam current measuring apparatus on a beam line irradiated from an ion source or an electron ray source onto the surface of a processed substance in order to measure the beam current value of said beam line from the output of said magnetic field sensor.

Claim 17 (original): A beam irradiation method comprising a measuring step of measuring, by using the beam current measuring method according to claim 16, a beam current of a beam generated using an ion source or an electron ray source,

a control step of feeding back said beam current value obtained in said measuring step to the control parameter of said ion source or electron ray source, and

an irradiating step of irradiating a beam current onto a processed substance, said beam current controlled using the control parameter obtained in said control step.

Claim 18 (currently amended): Beam irradiation apparatus comprising the beam current measuring apparatus according to any one of claims 1 through 15 claim 1.

Claim 19 (currently amended): A processed substance manufactured using ion implantation apparatus, electron beam exposure apparatus or accelerating apparatus comprising the beam current measuring apparatus according to any one of claims—1 through 15 claim 1.